2N6426 is a Preferred Device

Darlington Transistors

NPN Silicon

Features

• These are Pb–Free Devices*

MAXIMUM RATINGS

Rating	Symbol	Value	Unit
Collector – Emitter Voltage	V _{CEO}	40	Vdc
Collector – Base Voltage	V _{CBO}	40	Vdc
Emitter – Base Voltage	V _{EBO}	12	Vdc
Collector Current – Continuous	Ι _C	500	mAdc
Total Device Dissipation @ $T_A = 25^{\circ}C$ Derate above 25°C	PD	625 5.0	mW mW/°C
Total Device Dissipation @ $T_C = 25^{\circ}C$ Derate above $25^{\circ}C$	P _D	1.5 12	W mW/°C
Operating and Storage Junction Temperature Range	T _J , T _{stg}	-55 to +150	°C

THERMAL CHARACTERISTICS

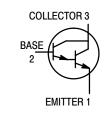
Characteristic	Symbol	Max	Unit	
Thermal Resistance, Junction-to-Ambient	$R_{\theta JA}$	200	°C/W	
Thermal Resistance, Junction-to-Case	$R_{\theta JC}$	83.3	°C/W	

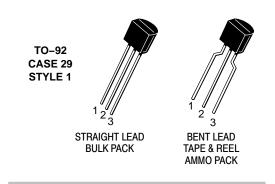
Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.



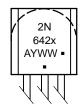
ON Semiconductor®

http://onsemi.com





MARKING DIAGRAM



x= 6 or 7A= Assembly LocationY= YearWW= Work Week•= Pb-Free Package

(Note: Microdot may be in either location)

ORDERING INFORMATION

See detailed ordering and shipping information in the package dimensions section on page 5 of this data sheet.

Preferred devices are recommended choices for future use and best overall value.

*For additional information on our Pb–Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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ELECTRICAL CHARACTERISTICS ($T_A = 25^{\circ}C$ unless otherwise noted)

Characteristic		Symbol	Min	Тур	Max	Unit
OFF CHARACTERISTICS						
Collector – Emitter Breakdown Voltage, (Note 1) ($I_C = 10 \text{ mAdc}, V_{BE} = 0$)		V _{(BR)CEO}	40	-	-	Vdc
Collector – Base Breakdown Voltage $(I_C = 100 \ \mu Adc, I_E = 0)$		V _{(BR)CBO}	40	-	-	Vdc
Emitter – Base Breakdown Voltage ($I_E = 10 \ \mu Adc, I_C = 0$)		$V_{(BR)EBO}$	12	-	_	Vdc
Collector Cutoff Current ($V_{CE} = 25 \text{ Vdc}, I_B = 0$)		I _{CES}	_	-	1.0	μAdc
Collector Cutoff Current (V_{CB} = 30 Vdc, I _E = 0)		I _{CBO}	_	-	50	nAdc
Emitter Cutoff Current (V_{BB} = 10 Vdc, I _C = 0)		I _{EBO}	-	-	50	nAdc
ON CHARACTERISTICS			•			
DC Current Gain, (Note 1) ($I_C = 10 \text{ mAdc}, V_{CE} = 5.0 \text{ Vdc}$)	2N6426 2N6427	h _{FE}	20,000 10,000	-	200,000 100,000	_
$(I_{C} = 100 \text{ mAdc}, V_{CE} = 5.0 \text{ Vdc})$	2N6426 2N6427		30,000 20,000	-	300,000 200,000	
$(I_{C} = 500 \text{ mAdc}, V_{CE} = 5.0 \text{ Vdc})$	2N6426 2N6427		20,000 14,000	-	200,000 140,000	
Collector – Emitter Saturation Voltage ($I_C = 50 \text{ mAdc}, I_B = 0.5 \text{ mAdc}$) ($I_C = 500 \text{ mAdc}, I_B = 0.5 \text{ mAdc}$		V _{CE(sat)}		0.71 0.9	1.2 1.5	Vdc
Base – Emitter Saturation Voltage (I _C = 500 mAdc, I _B = 0.5 mAdc)		V _{BE(sat)}	-	1.52	2.0	Vdc
Base – Emitter On Voltage (I _C = 50 mAdc, V _{CE} = 5.0 Vdc)		$V_{\text{BE(on)}}$	-	1.24	1.75	Vdc
SMALL-SIGNAL CHARACTERISTICS						
Output Capacitance ($V_{CB} = 10 \text{ Vdc}, I_E = 0, f = 1.0 \text{ MHz}$)		C _{obo}	-	5.4	7.0	pF
Input Capacitance $(V_{EB} = 1.0 \text{ Vdc}, I_C = 0, f = 1.0 \text{ MHz})$		C _{ibo}	-	10	15	pF
Input Impedance ($I_C = 10 \text{ mAdc}, V_{CE} = 5.0 \text{ Vdc}, f = 1.0 \text{ kHz}$)	2N6426 2N6427	h _{ie}	100 50		2000 1000	kΩ
Small–Signal Current Gain (I _C = 10 mAdc, V _{CE} = 5.0 Vdc, f = 1.0 kHz)	2N6426 2N6427	hfe	20,000 10,000	_		_
Current–Gain – High Frequency (I _C = 10 mAdc, V _{CE} = 5.0 Vdc, f = 100 MHz)	2N6426 2N6427	h _{fe}	1.5 1.3	2.4 2.4		-
Output Admittance (I _C = 10 mAdc, V _{CE} = 5.0 Vdc, f = 1.0 kHz)		h _{oe}	-	_	1000	μmhos
Noise Figure (I _C = 1.0 mAdc, V _{CE} = 5.0 Vdc, R _S = 100 kΩ, f = 1.0 kHz)		NF	-	3.0	10	dB

1. Pulse Test: Pulse Width \leq 300 µs; Duty Cycle \leq 2.0%.

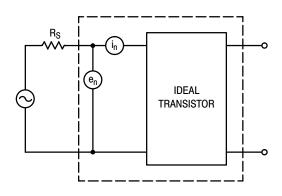
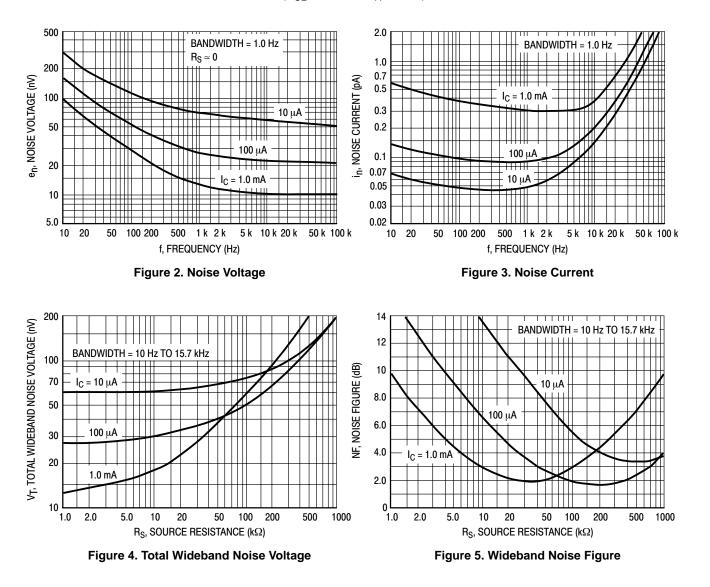


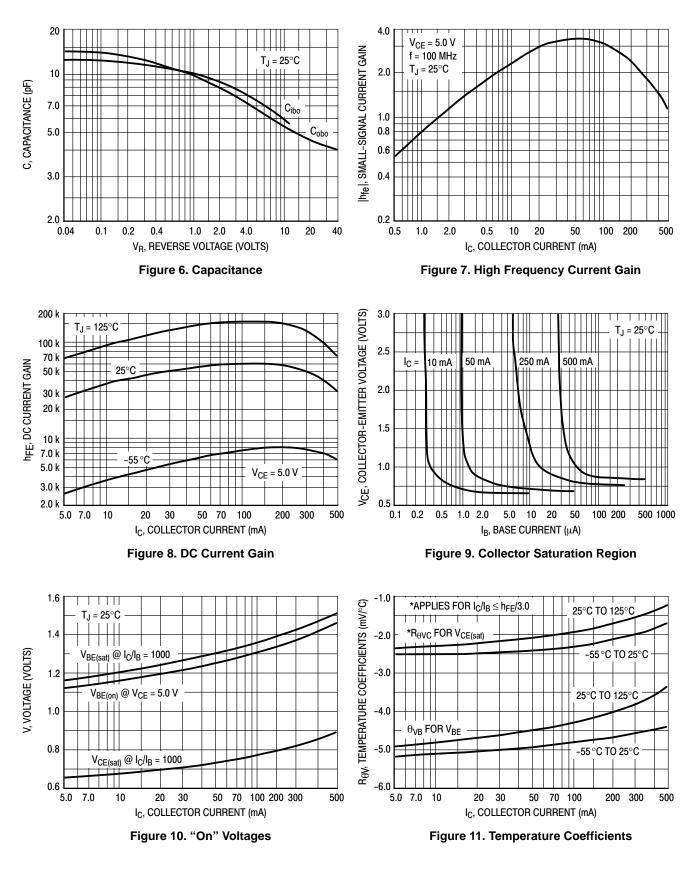
Figure 1. Transistor Noise Model

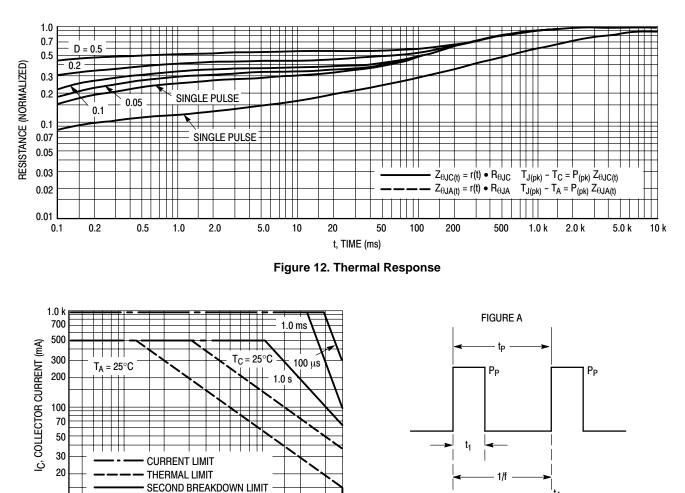
NOISE CHARACTERISTICS

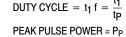
 $(V_{CE} = 5.0 \text{ Vdc}, T_A = 25^{\circ}C)$



SMALL-SIGNALCHARACTERISTICS







Design Note: Use of Transient Thermal Resistance Data

ORDERING INFORMATION

10

0.4 0.6

1.0

2.0

4.0 6.0

V_{CE}, COLLECTOR-EMITTER VOLTAGE (VOLTS) Figure 13. Active Region Safe Operating Area

10

20

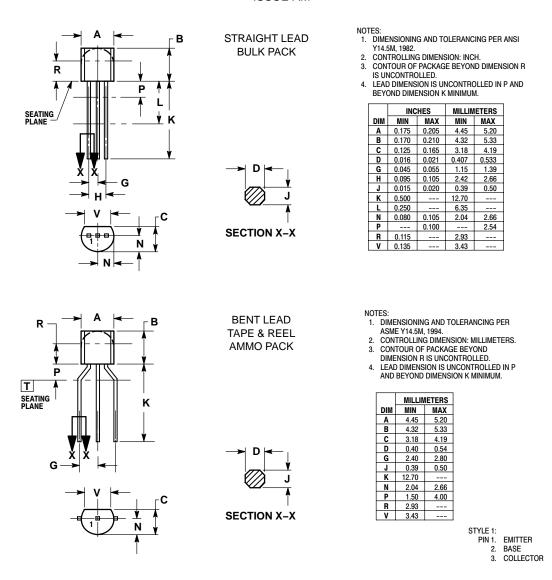
40

Device	Package	Shipping [†]
2N6426G	TO-92 (Pb-Free)	5,000 Units / Bulk
2N6426RLRAG	TO-92 (Pb-Free)	2,000 / Tape & Ammo
2N6427G	TO-92 (Pb-Free)	5,000 Units / Bulk
2N6427RLRAG	TO-92 (Pb-Free)	2,000 / Tape & Ammo

+For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

PACKAGE DIMENSIONS

TO-92 (TO-226) CASE 29-11 ISSUE AM



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